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APPLICATION NO	. F	LING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	ATTORNEY DOCKET NO. CONFIRMATION NO.	
10/722,635		11/26/2003	Ching Man Stanley Tsui	P/4076-62	7319	
2352	7590	08/12/2004		EXAM	EXAMINER	
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NEW YOR				ART UNIT	PAPER NUMBER	
	,			2829		

DATE MAILED: 08/12/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	
	10/722,635	STANLEY TSUI ET AL.	
Office Action Summary	Examiner	Art Unit	
	Jermele M. Hollington	2829	
The MAILING DATE of this communical Period for Reply	tion appears on the cover sheet t	vith the correspondence address	
A SHORTENED STATUTORY PERIOD FOR THE MAILING DATE OF THIS COMMUNICA - Extensions of time may be available under the provisions of 3 after SIX (6) MONTHS from the mailing date of this communi - If the period for reply specified above is less than thirty (30) d - If NO period for reply specified above, the maximum statute - Failure to reply within the set or extended period for reply will Any reply received by the Office later than three months after earned patent term adjustment. See 37 CFR 1.704(b).	ATION. FOR 1.136(a). In no event, however, may a cation. ays, a reply within the statutory minimum of the corp of will apply and will expire SIX (6) MC, by statute, cause the application to become	reply be timely filed irty (30) days will be considered timely. NTHS from the mailing date of this communication ABANDONED (35 U.S.C. § 133).	ı
Status			
1) Responsive to communication(s) filed	on 26 November 2003.		
•	☐ This action is non-final.	5	
3) Since this application is in condition for closed in accordance with the practice			i
Disposition of Claims			
4) Claim(s) 1-19 is/are pending in the approximate the above claim(s) is/are 5) Claim(s) is/are allowed. 6) Claim(s) 1-8 and 10-19 is/are rejected. 7) Claim(s) 9 is/are objected to. 8) Claim(s) are subject to restriction	withdrawn from consideration.	\.	
Application Papers			
9) The specification is objected to by the E 10) The drawing(s) filed on 26 November 2 Applicant may not request that any objection Replacement drawing sheet(s) including the short of	2003 is/are: a) ☐ accepted or b) on to the drawing(s) be held in abey be correction is required if the drawing.	ance. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.121(c	1).
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for a) All b) Some * c) None of: 1. Certified copies of the priority do 2. Certified copies of the priority do 3. Copies of the certified copies of application from the International	ocuments have been received. Ocuments have been received in the priority documents have been all Bureau (PCT Rule 17.2(a)).	Application No en received in this National Stage	
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-3) Information Disclosure Statement(s) (PTO-1449 or PT Paper No(s)/Mail Date	0-948) Paper N	v Summary (PTO-413) o(s)/Mail Date f Informal Patent Application (PTO-152) 	

DETAILED ACTION

Information Disclosure Statement

The listing of references in the specification is not a proper information disclosure statement. 37 CFR 1.98(b) requires a list of all patents, publications, or other information submitted for consideration by the Office, and MPEP § 609 A(1) states, "the list may not be incorporated into the specification but must be submitted in a separate paper."

Therefore, unless the examiner on form PTO-892 has cited the references, they have not been considered [see page 2, line 28].

Drawings

- 2. The drawings are objected to as failing to comply with 37 CFR 1.84(p)(5) because they include the following reference character(s) not mentioned in the description: item no. 32 in Figs 2-3.
- 3. The drawings are objected to as failing to comply with 37 CFR 1.84(p)(4) because reference characters "guide blocks" and "manual test jig" have both been used to designate item no. 36.
- 4. The drawings are objected to under 37 CFR 1.83(a). The drawings must show every feature of the invention specified in the claims. Therefore, a distal end [claims 1 and 13] must be shown or the feature(s) canceled from the claim(s). No new matter should be entered.

Corrected drawing sheets in compliance with 37 CFR 1.121(d) are required in reply to the Office action to avoid abandonment of the application. Any amended replacement drawing sheet should include all of the figures appearing on the immediate prior version of the sheet, even if only one figure is being amended. The figure or figure

number of an amended drawing should not be labeled as "amended." If a drawing figure is to be canceled, the appropriate figure must be removed from the replacement sheet, and where necessary, the remaining figures must be renumbered and appropriate changes made to the brief description of the several views of the drawings for consistency. Additional replacement sheets may be necessary to show the renumbering of the remaining figures. The replacement sheet(s) should be labeled "Replacement Sheet" in the page header (as per 37 CFR 1.84(c)) so as not to obstruct any portion of the drawing figures. If the changes are not accepted by the examiner, the applicant will be notified and informed of any required corrective action in the next Office action. The objection to the drawings will not be held in abeyance.

Specification

5. The title of the invention is not descriptive. A new title is required that is clearly indicative of the invention to which the claims are directed.

Claim Rejections - 35 USC § 103

- 6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 7. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under

37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

8. Claims 1-8 and 10-19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Langgard (5175493) in view of Staab (5570033).

Regarding claim 1, Langgard discloses [see Figs. 5-7] a unitary spring contact probe (spring probe 4) comprising a resilient spring section (spring 43), a plunger section (plunger 35) extending from a distal end (head portion 39) of the resilient spring section (43) for contacting a semiconductor device under test (DUT 75 see Fig. 7) and a stopper (crimp 41) substantially transversely to an axial direction of the plunger section (35). However, he does not disclose the stopper projecting from the plunger as claimed. Staab discloses [see Fig. 2] a spring contact probe (spring probe 12), a plunger section (isolation rings 26) and a stopper (BGA device stop 22) [see col. 3, lines 8-10] projecting from the plunger section (26). Further, Staab teaches that the addition of stopper 22 is advantageous because it prevents over-insertion of a BGA device into a plate and limits the amount of compression of the spring probes, which extend the life of the probe and the plate. It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify the apparatus of Langgard by adding the stopper to project from the plunger section as taught by Staab in order to prevent over-insertion and limit the amount of compression of the spring probes so that the to life of the spring probe could be extend during testing.

Regarding claim 2, Langgard discloses the probe (4) is formed from a wire-like material [slender rod].

Regarding claim 3, Langgard discloses a second plunger section (plunger 35 bottom portion in Fig. 7 of probe 4) at another distal end (head portion 39 bottom portion in Fig. 7 of probe 4) of the resilient spring section (43) that is opposite the plunger section (35).

Regarding claim 4, Langgard discloses the second plunger section (plunger 35 bottom portion in Fig. 7 of probe 4) extends out of the spring section (43) in a substantially straight line in the same general axial direction as the spring section (43).

Regarding claim 5, Langgard discloses the second plunger section (plunger 35 bottom portion in Fig. 7 of probe 4) extends substantially parallel to the plunger section (35) when the spring section (43) is uncompressed.

Regarding claim 6, Langgard discloses the plunger section (35 top probe 4 in Fig. 7) and the second plunger section (35 bottom probe 4 in Fig. 7) lie on opposite sides of an axial plane passing perpendicularly through a center (connecting pins 68) of the spring section (44).

Regarding claim 7, Langgard discloses the plunger section (35 top probe 4 in Fig. 7) and the second plunger section (35 bottom probe 4 in Fig. 7) are inherently [see Note below claim] fashioned from a single strip of material [beryllium cooper see col. 4, lines 20-22].

[Note: Although the prior art does not specifically disclose the plunger section material, this feature is seen to be an inherent teaching of the plunger since the barrel 2, which is a part of the probe, disclose the material and it is known in the art that if one part of the spring probe material is disclose that the whole spring probe is made of the same material [see U.S. Patent 5,818,248 col. 4, lines 33-38 which states:

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"...spring probes are made from a beryllium copper alloy and include an outer receptacle, a barrel in the outer receptacle, a plunger 17 projecting from the barrel, and a compression spring inside the barrel..."]]

Regarding claim 8, Langgard discloses a second stopper (crimp 41 located on the bottom probe 4 in Fig. 7) substantially transversely to an axial direction of the second plunger section (35). However, he does not disclose the stopper projecting from the plunger as claimed. Staab discloses [see Fig. 2] a spring contact probe (spring probe 12), a plunger section (isolation rings 26) and a stopper (BGA device stop 22) [see col. 3, lines 8-10] projecting from the plunger section (26). Further, Staab teaches that the addition of stopper 22 is advantageous because it prevents over-insertion of a BGA device into a plate and limits the amount of compression of the spring probes, which extend the life of the probe and the plate. It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify the apparatus of Langgard by adding the stopper to project from the plunger section as taught by Staab in order to prevent over-insertion and limit the amount of compression of the spring probes so that the to life of the spring probe could be extend during testing.

Regarding claims 10-11, Langgard inherently [see Note below claim] discloses the spring contact probe (4), the spring section (43), plunger section (35) and stopper (41) are fashioned from a single strip of material [beryllium copper see col. 4, lines 20-22].

[Note: Although the prior art does not specifically disclose the spring contact probe, the spring section, plunger section and stopper material, this feature is seen to be an inherent teaching of the plunger since the barrel 2, which is a part of the probe, disclose the material and it is known in the art that if one part of the spring probe material is disclose that the whole spring probe is made of the same material [see U.S. Patent 5,818,248 col. 4, lines 33-38 which states: "... spring probes are made from a beryllium copper

alloy and include an outer receptacle, a barrel in the outer receptacle, a plunger 17 projecting from the barrel, and a compression spring inside the barrel..."]]

Regarding claim12, Langgard discloses the spring contact probe (4) is inherently [see Note below claim] plated with a material selected from the group consisting of nickel, palladium, hard gold and rhodium [see col. 4, lines 20-22].

[Note: Although the prior art does not specifically disclose the spring contact probe, the spring section, plunger section and stopper material, this feature is seen to be an inherent teaching of the plunger since the barrel 2, which is a part of the probe, disclose the material and it is known in the art that if one part of the spring probe material is disclose that the whole spring probe is made of the same material [see U.S. Patent 5,818,248 col. 4, lines 33-38 which states: "...spring probes are made from a beryllium copper alloy and include an outer receptacle, a barrel in the outer receptacle, a plunger 17 projecting from the barrel, and a compression spring inside the barrel..."]]

Regarding claim 13, Langgard discloses [see Figs. 5-7] an apparatus comprising a unitary spring contact probe (spring probe 4) comprising a resilient spring section (spring 43), a plunger section (plunger 35) extending from a distal end (head portion 39) of the resilient spring section (43) for contacting a semiconductor device under test (DUT 75 see Fig. 7) and a stopper (crimp 41) substantially transversely to an axial direction of the plunger section (35), one or more insulative guiding holders (shield 5) for mounting the spring contact probes (4), and a retainer mechanism (barrel 66) coupled to the stoppers (41) of the spring contact probes (4) for securing the spring contact probes (4) to the insulative guiding holders (5). However, he does not disclose the stopper projecting from the plunger as claimed. Staab discloses [see Fig. 2] a spring contact probe (spring probe 12), a plunger section (isolation rings 26) and a stopper (BGA device stop 22) [see col. 3, lines 8-10] projecting from the plunger section (26). Further, Staab teaches that the

addition of stopper 22 is advantageous because it prevents over-insertion of a BGA device into a plate and limits the amount of compression of the spring probes, which extend the life of the probe and the plate. It would have been obvious to a person having ordinary skill in the art at the time the invention was made to modify the apparatus of Langgard by adding the stopper to project from the plunger section as taught by Staab in order to prevent over-insertion and limit the amount of compression of the spring probes so that the to life of the spring probe could be extend during testing.

Regarding claim 14, Langgard discloses the retainer mechanism (barrel 66) comprises a retainer plate (barrel core 3) including holes [not number but see Fig. 4] that allow the plunger sections (35) of the spring contact probes (4) to protrude from a surface of the retainer plate (3) for contacting the semiconductor device (test site 73).

Regarding claim 15, Langgard discloses cavities [not number but shown in Fig. 7] in the insulative guiding holders (5) for introducing purging air onto the spring contact probes (4).

Regarding claim16, Langgard discloses an electrical circuit (connector site 78) contacted by an end of the spring contact probe (4) that is opposite the plunger section (35), wherein the electrical circuit (78) is coupled to signal processing resources (board 77) of the apparatus.

Regarding claim 17, Langgard discloses a second plunger section (35) at said end of the resilient spring section (43) that is opposite the plunger section (35) for contacting the electrical circuit (78).

Regarding claim 18, Langgard discloses a second retaining mechanism (barrel 66) coupled to another stopper (41) of the spring contact probes (4) projecting from the

second plunger section (35) for securing the spring contact probes (4) to the insulative guiding holders (5).

Regarding claim 19, Langgard discloses the second retaining mechanism (66) comprises a retainer plate (barrel core 3) including holes [not number but shown in the figures] that allow the second plunger section (35) of the spring contact probe (4) to protrude from a surface of the second retainer plate (3) for contacting the electrical circuit (78).

Conclusion

- 9. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Petlock, Jr. (4307928), Katz (4438397), Kruger et al (4773877), Sabin (4783624), Nanzai (4801876), Golden et al (5196789), Richards (5225773), Staab (5585739), Johnston (5667410), St. Onge (5818248), Stowers et al (5936421), Caggiano et al (6401048) and Yeghiayan et al (6570399) disclose a method and apparatus for spring probe device.
- 10. Claim 9 is objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- The following is a statement of reasons for the indication of allowable subject matter: regarding claim 9, in the examiner's opinion, it would not have been obvious to a person of ordinary skill in the art to have the stopper configured to act as a thermal device for facilitating the dissipation of heat from the spring contact probe with the prior art to get the results of the claimed invention.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jermele M. Hollington whose telephone number is (571) 272-1960. The examiner can normally be reached on M-F (9:00-4:30 EST) First Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kamand Cuneo can be reached on (517) 272-1957. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Jermele M. Hollington Examiner

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JMH August 6, 2004